

workshop

Hoervelsinger Weg 6, D-89081 Ulm, Germany
Tel. +49 (0) 731 140 700, Fax. +49 (0) 731 140 7020
www.witec.de, info@witec.de

WITec
focus innovations

Introduction to Confocal Raman and Scanning Probe Microscopy

Wednesday, April 11, 2007, 14:30 - 15:50
Universitat de Valencia, Facultat de Farmacia'
Av. Vicent Andres, Estelles, 46100 Burjassot
Auditorium 7

The workshop will present a detailed introduction to the operational principles and instrumental configurations relevant to Confocal Raman and Scanning Probe Microscopy (AFM, NSOM, Pulsed Force Mode). The speakers will cover several aspects of modern Raman imaging and its fields of applications. Scientists interested in how to structurally and chemically identify and image the compounds of a sample at the highest spatial resolution are invited to participate.

Typical research fields for SPM and confocal Raman imaging are pharmaceuticals and cosmetics, materials and polymer sciences, archaeology and geology, forensics, coatings, thin films and all fields in which a clear identification of the distribution of chemical compounds is a necessity. Our speakers are Dr. Fernando Vargas, Applications Scientist with WITec and Dr. Christian Matthäus, Research Associate, Northeastern University, Boston, USA.

The workshop is free of charge. To secure space for everybody, registration is appreciated. To register please send your contact information to events@witec.de or visit our booth at the FOM exhibition.

Take full advantage of the Focus On Microscopy Conference and broaden your expertise in Raman and SPM imaging by attending our presentation.

Program

Wednesday, April 11, 2007

14.30 - 15.00	Dr. Fernando Vargas	Introduction to Confocal Raman Microscopy
15.00 - 15.30	Dr. Christian Matthäus	Confocal Raman Microscopy in Cell Biology and Pharmaceutical Sciences
15.30 - 15.50	Dr. Fernando Vargas	Combining High-Resolution Optical and Scanning Probe Microscopy



Fig. 1: Confocal Raman Microscope WITec alpha300 R

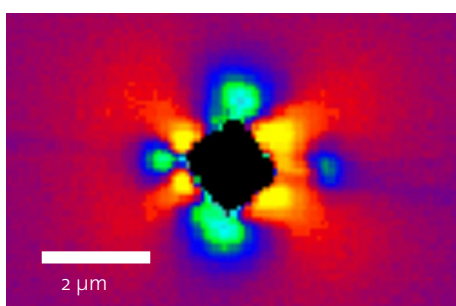


Fig. 2: Stress map around a Vickers indent on a silicon wafer. 10 000 spectra with an integration time of only 70ms per spectrum.

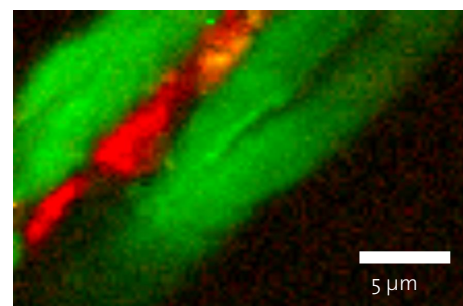


Fig. 3: Raman Image of a Textile Fiber